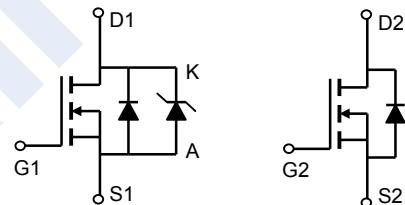
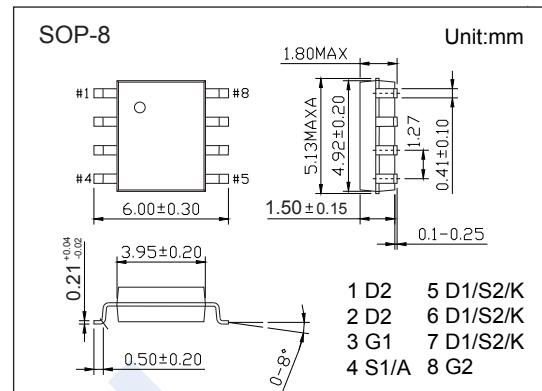


## Dual N-Channel MOSFET

### AO4912 (KO4912)

#### ■ Features

- N-Channel 1
  - $V_{DS(V)} = 30V$
  - $I_D = 8.5 A$  ( $V_{GS} = 10V$ )
  - $R_{DS(ON)} < 17m\Omega$  ( $V_{GS} = 10V$ )
  - $R_{DS(ON)} < 25m\Omega$  ( $V_{GS} = 4.5V$ )
  - $V_{DS(V)} = 30V$ ,  $I_F = 3A$ ,  $V_F < 0.5V @ 1A$
- N-Channel 2
  - $V_{DS(V)} = 30V$
  - $I_D = 7 A$  ( $V_{GS} = 10V$ )
  - $R_{DS(ON)} < 26m\Omega$  ( $V_{GS} = 10V$ )
  - $R_{DS(ON)} < 31m\Omega$  ( $V_{GS} = 4.5V$ )



#### ■ Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	N-Channel 1	Schottky	N-Channel 2	Unit
Drain-Source Voltage	$V_{DS}$	30		30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$		$\pm 12$	
Schottky Reverse Voltage	$V_{KA}$		30		
Continuous Drain Current	$I_D$ $T_a=25^\circ C$	8.5		7	A
	$I_D$ $T_a=70^\circ C$	6.8		6.4	
Pulsed Drain Current	$I_{DM}$	40		30	
Continuous Forward Current	$I_F$ $T_a=25^\circ C$		3		A
	$I_F$ $T_a=70^\circ C$		2.2		
Pulsed Diode Forward Current	$I_{FM}$		20		
Avalanche Current	$I_{AR}$	17		15	
Repetitive Avalanche Energy	$E_{AR}$	43		34	mJ
Power Dissipation	$P_D$ $T_a=25^\circ C$		2		W
	$P_D$ $T_a=70^\circ C$		1.28		
Thermal Resistance.Junction- to-Ambient	$R_{thJA}$ $t \leq 10s$		62.5		°C/W
	$R_{thJA}$ Steady-State		110		
Thermal Resistance.Junction- to-Lead	$R_{thJL}$		40		
Junction Temperature	$T_J$		150		
Storage Temperature Range	$T_{stg}$		-55 to 150		°C

## Dual N-Channel MOSFET

### AO4912 (KO4912)

■ N-Channel 1 Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V <sub>DSS</sub>	I <sub>D</sub> =250 μ A, V <sub>GS</sub> =0V	30			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V			0.05	mA
		V <sub>DS</sub> =30V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C			10	
		V <sub>DS</sub> =30V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C			20	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250 μ A	1		3	V
Static Drain-Source On-Resistance	R <sub>D(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =8.5A			17	mΩ
		V <sub>GS</sub> =10V, I <sub>D</sub> =8.5A T <sub>J</sub> =125°C			24	
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =7A			25	
On State Drain Current	I <sub>D(on)</sub>	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =5V	30			A
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =5V, I <sub>D</sub> =8.5A		23		S
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, f=1MHz		971	1165	pF
Output Capacitance (FET + Schottky)	C <sub>oss</sub>			190		
Reverse Transfer Capacitance	C <sub>rss</sub>			110	154	
Gate Resistance	R <sub>G</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz	0.35		0.85	Ω
Total Gate Charge (10V)	Q <sub>g</sub>	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =8.5A		19.2	23	nC
Total Gate Charge (4.5V)				9.36	11.2	
Gate Source Charge	Q <sub>gs</sub>			2.6		
Gate Drain Charge	Q <sub>gd</sub>			4.2		
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, R <sub>L</sub> =1.8Ω, R <sub>GEN</sub> =3Ω		5.2	7.5	ns
Turn-On Rise Time	t <sub>r</sub>			4.4	6.5	
Turn-Off Delay Time	t <sub>d(off)</sub>			17.3	25	
Turn-Off Fall Time	t <sub>f</sub>			3.3	5	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 8.5A, dI/dt= 100A/us		19.3	23	nC
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			9.4	11	
Body-Diode + Schottky Continuous Current	I <sub>S</sub>				3.5	A
Diode + Schottky Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =1A, V <sub>GS</sub> =0V			0.5	V

Note. The static characteristics in Figures 1 to 6 are obtained using 300 μs pulses, duty cycle 0.5% max.

■ Marking

Marking	4912 KA****
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## Dual N-Channel MOSFET

### AO4912 (KO4912)

■ N-Channel 2 Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V <sub>DSS</sub>	I <sub>D</sub> =250 μ A, V <sub>GS</sub> =0V	30			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>D</sub> =30V, V <sub>GS</sub> =0V			1	uA
		V <sub>D</sub> =30V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C			5	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>D</sub> =0V, V <sub>GS</sub> =±12V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>D</sub> =V <sub>GS</sub> , I <sub>D</sub> =250 μ A	1		2	V
Static Drain-Source On-Resistance	R <sub>D(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =7A			26	m Ω
		V <sub>GS</sub> =10V, I <sub>D</sub> =7A T <sub>J</sub> =125°C			38	
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =6A			31	
On State Drain Current	I <sub>D(on)</sub>	V <sub>GS</sub> =4.5V, V <sub>D</sub> =5V	25			A
Forward Transconductance	g <sub>FS</sub>	V <sub>D</sub> =5V, I <sub>D</sub> =7A		22		S
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>D</sub> =15V, f=1MHz		590	710	pF
Output Capacitance	C <sub>oss</sub>			162		
Reverse Transfer Capacitance	C <sub>rss</sub>			40	56	
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> =0V, V <sub>D</sub> =0V, f=1MHz	0.2		0.6	Ω
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> =4.5V, V <sub>D</sub> =15V, I <sub>D</sub> =7A		6.04	7.3	nC
Gate Source Charge	Q <sub>gs</sub>			1.46		
Gate Drain Charge	Q <sub>gd</sub>			2.56		
Turn-On DelayTime	t <sub>d(on)</sub>	V <sub>GS</sub> =10V, V <sub>D</sub> =15V, R <sub>L</sub> =2.2Ω, R <sub>GEN</sub> =3Ω		3.7	5.5	ns
Turn-On Rise Time	t <sub>r</sub>			3.5	5.5	
Turn-Off DelayTime	t <sub>d(off)</sub>			14.9	22	
Turn-Off Fall Time	t <sub>f</sub>			2.5	4	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 7A, dI/dt= 100A/us		21.2	26	nC
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			14.2	21	
Body-Diode + Schottky Continuous Current	I <sub>s</sub>				3	A
Diode Forward Voltage	V <sub>SD</sub>	I <sub>s</sub> =1A, V <sub>GS</sub> =0V			1	V

Note. The static characteristics in Figures 1 to 6 are obtained using 300 μs pulses, duty cycle 0.5% max.

## Dual N-Channel MOSFET

AO4912 (KO4912)

■ N-Channel 1 Typical Characteristics

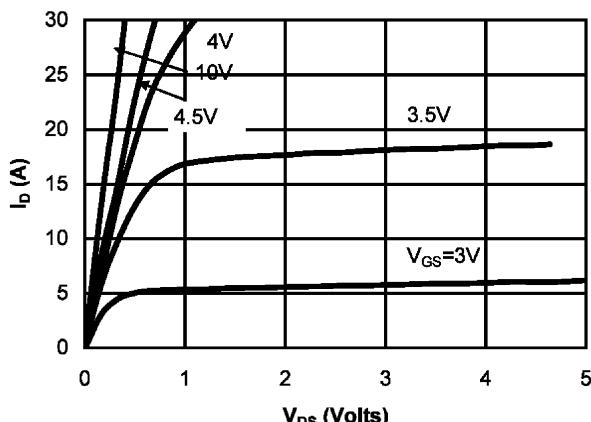


Fig 1: On-Region Characteristics

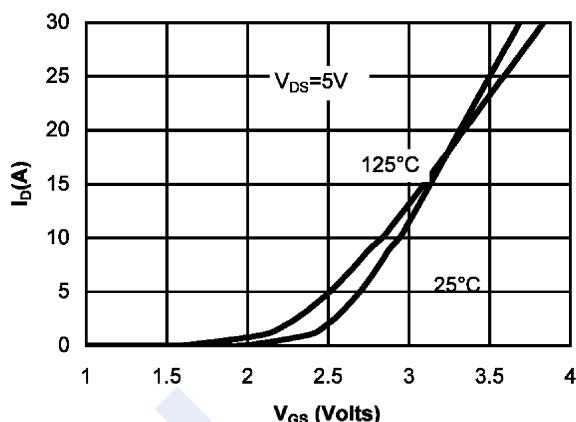


Figure 2: Transfer Characteristics

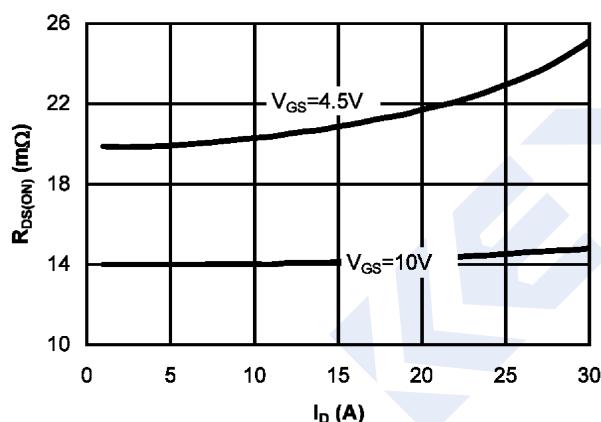


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

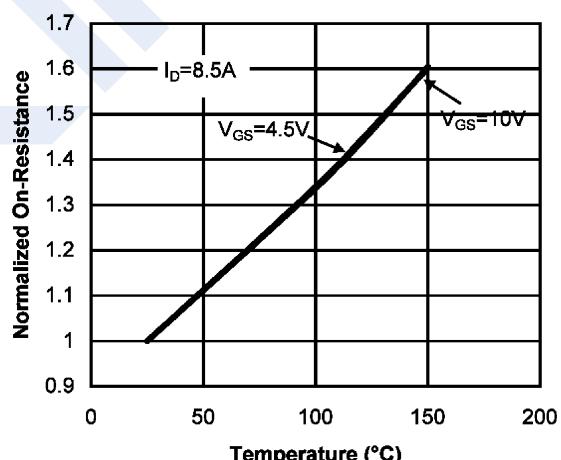


Figure 4: On resistance vs. Junction Temperature

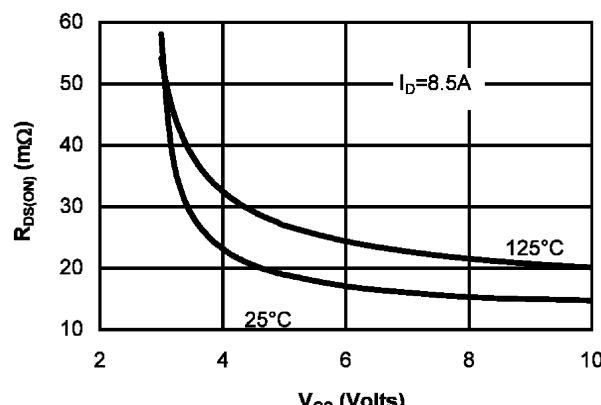
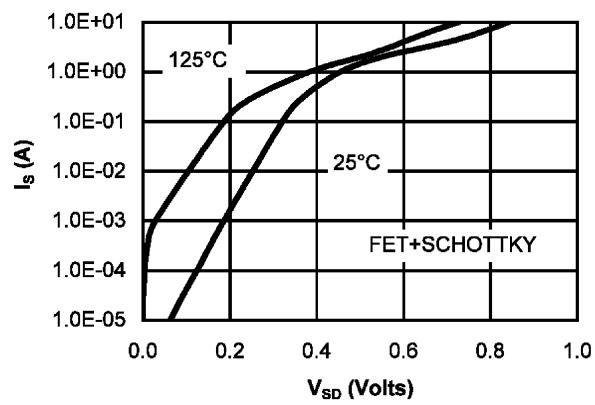


Figure 5: On resistance vs. Gate-Source Voltage

Figure 6: Body-Diode Characteristics  
(Note F)

## Dual N-Channel MOSFET

### AO4912 (KO4912)

■ N-Channel 1 Typical Characteristics

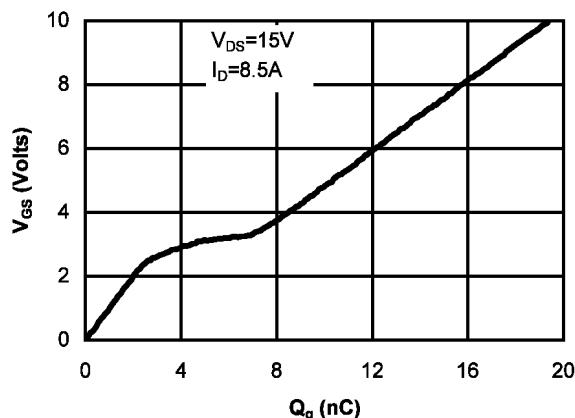


Figure 7: Gate-Charge Characteristics

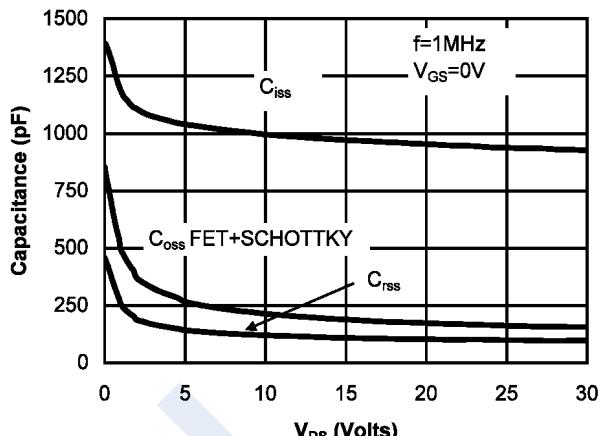


Figure 8: Capacitance Characteristics

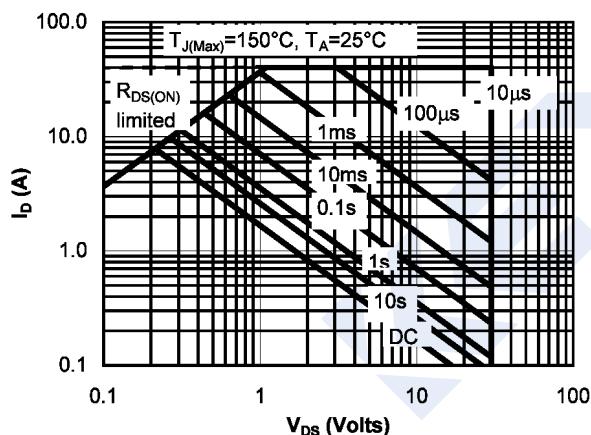


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

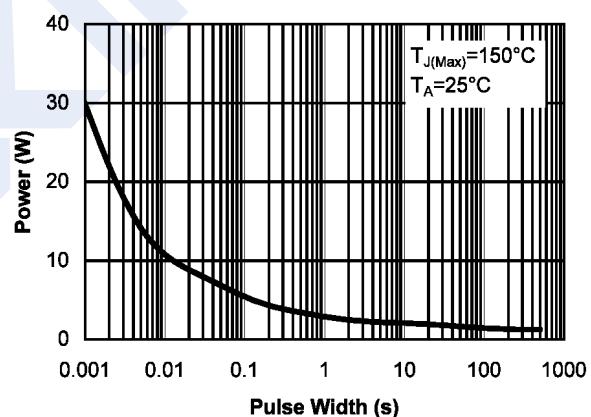


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

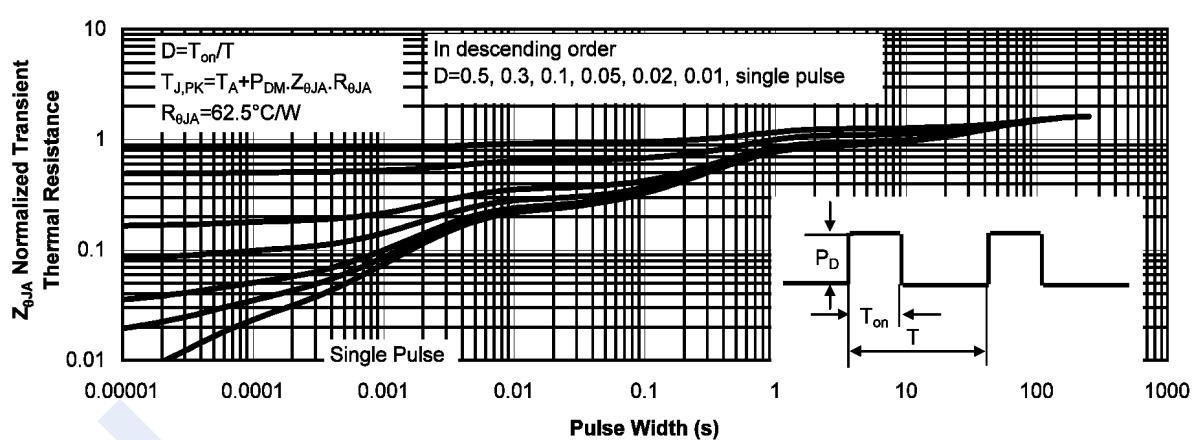
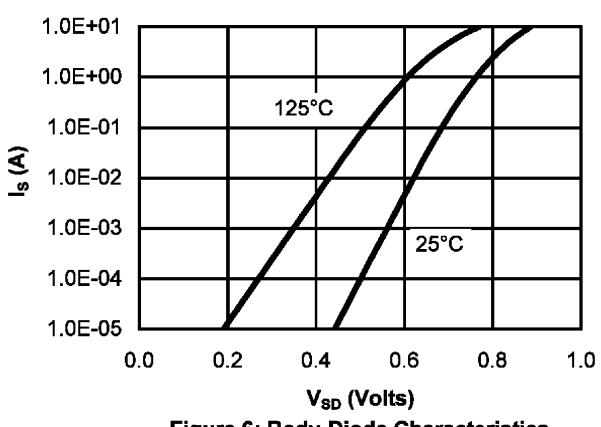
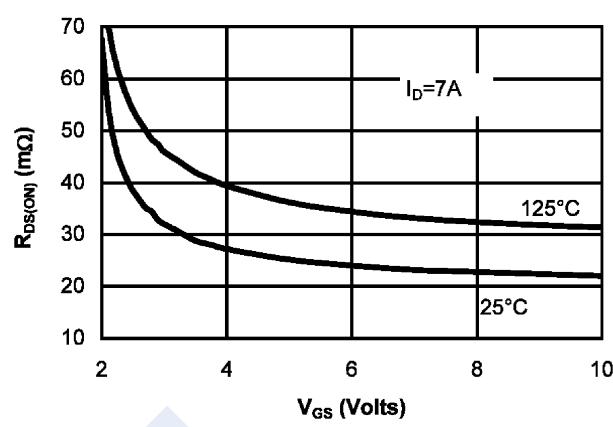
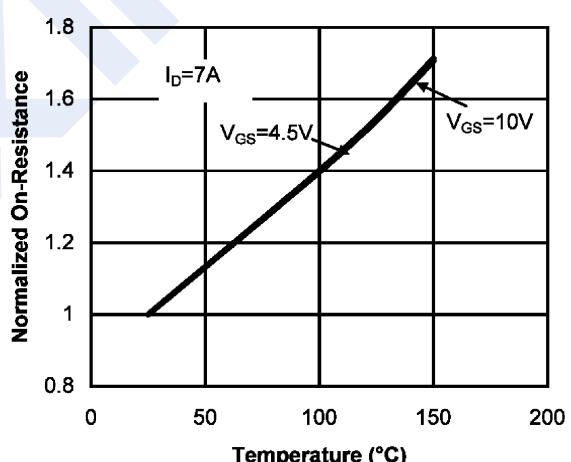
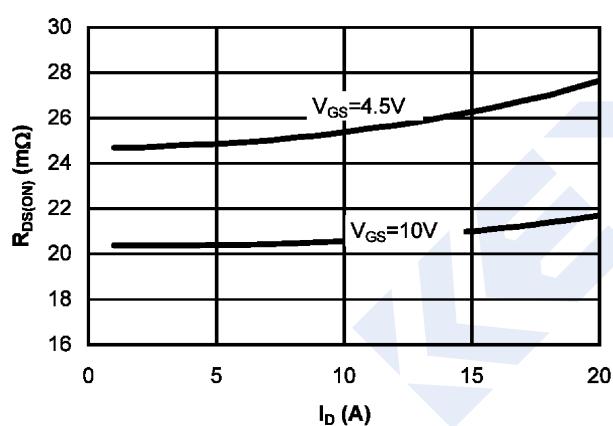
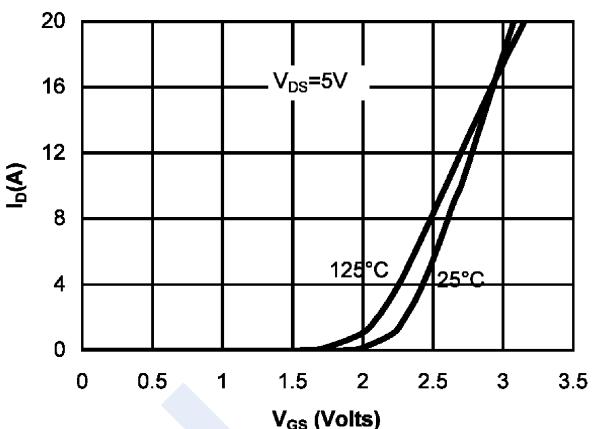
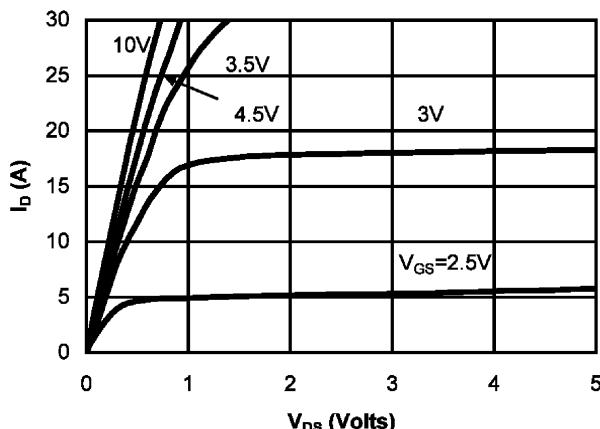


Figure 11: Normalized Maximum Transient Thermal Impedance

## Dual N-Channel MOSFET

### AO4912 (KO4912)

■ N-Channel 2 Typical Characteristics



## Dual N-Channel MOSFET

### AO4912 (KO4912)

■ N-Channel 2 Typical Characteristics

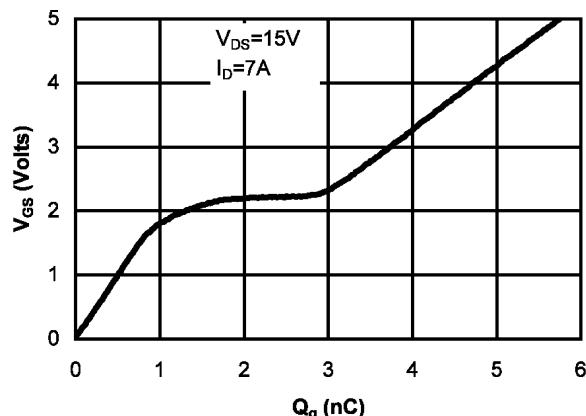


Figure 7: Gate-Charge Characteristics

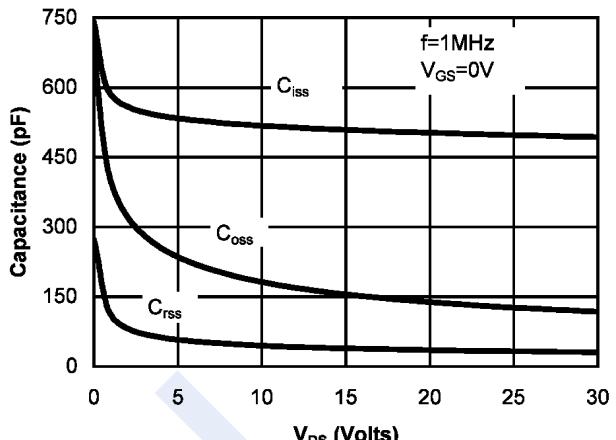


Figure 8: Capacitance Characteristics

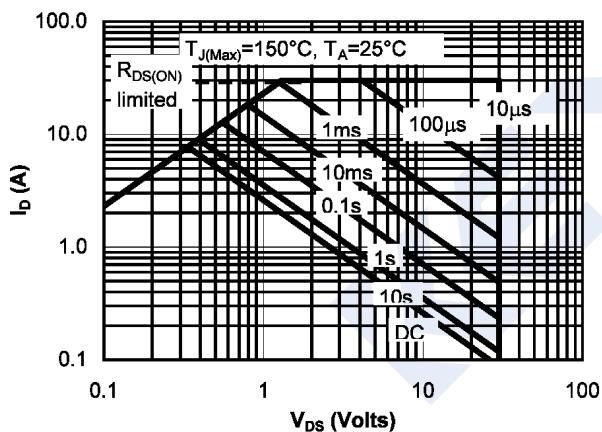


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

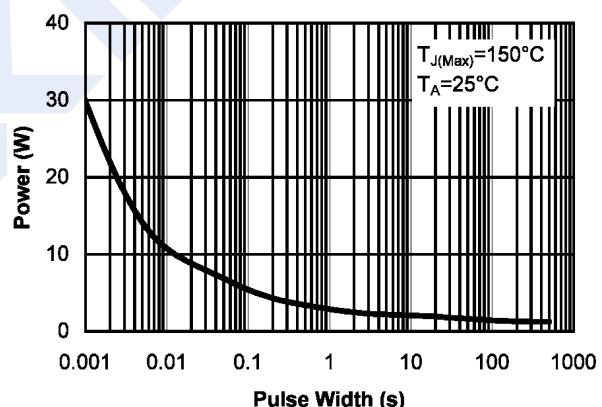


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

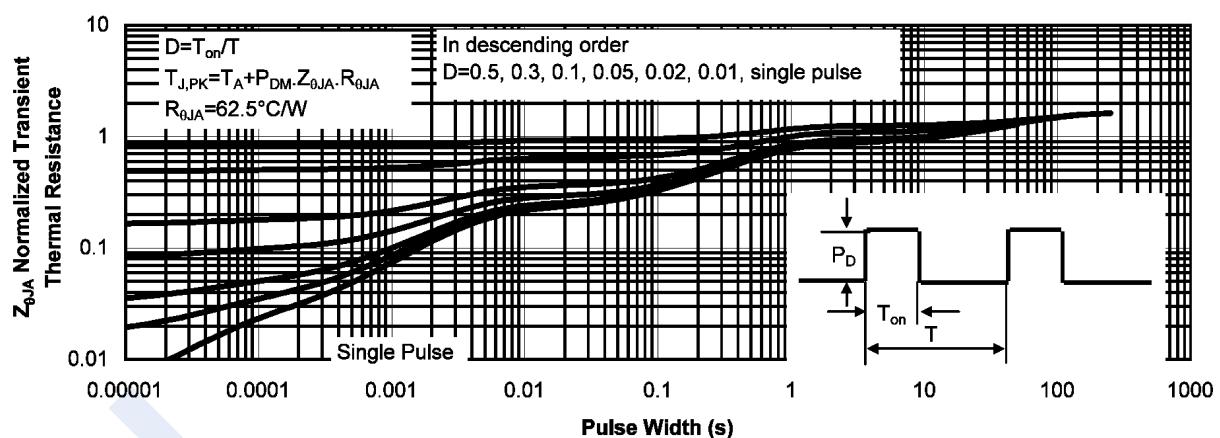


Figure 11: Normalized Maximum Transient Thermal Impedance